Notice of References Cited

Ī	Application/Control No.	Applicant(s)/Pater	nt Under
	10/575,332	Reexamination OBATA ET AL.	
	Examiner	Art Unit	
	Elizabeth E. Mulvanev	1794	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,544,616 B2	04-2003	Nee, Han H.	428/64.1
*	В	US-7,018,696 B2	03-2006	Nee, Han H.	428/64.1
*	O	US-2006/0093510 A1	05-2006	Obata et al.	420/501
*	D	US-2007/0026187 A1	02-2007	Obata et al.	428/064.2
*	Е	US-2007/0148033 A1	06-2007	Obata et al.	420/505
*	F	US-7,384,677 B2	06-2008	Nee, Han H.	428/64.1
*	G	US-7,413,618 B2	08-2008	Obata et al.	148/430
	н	US-		-	
	-	US-			
	7	US-			
	К	US-			
	L	US-			
	м	US-			

FOREIGN PATENT DOCUMENTS

	FOREIGN PATENT DOCUMENTS					
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003160860 A	06-2003	Japan	MORI, AKIRA	C23C 14/34
	0	JP 2003160859 A	06-2003	Japan	MORI, AKIRA	C23C 14/34
	Р	JP 2002319185	10-2002	Japan	Shimizu	
	Q	JP 2002226927	08-2002	Japan	Murata	
	R					
	s					
	т					

NON DATENT DOCUMENTS

*	NON-PAIENT DOCUMENTS			
_		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U			
	v			
	w			
	x			

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.